This part is no longer available from Fox, please contact IDT for this product.

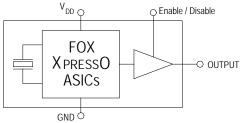
Model: FXO-LC33 SERIES

LVDS 3.2 x 2.5mm 3.3V Oscillator

Freq: 0.75 MHz to 1.35GHz

Features

- XTREMELY Low Jitter
- Low Cost
- XPRESS Delivery
- Frequency Resolution to six decimal places
- Stabilities to ± 25 PPM
- -20 to +70°C or -40 to +85°C operating temperatures
- Tri-State Enable / Disable Feature
- Industry Standard Package, Footprint & Pin-Out
- Fully RoHS and REACH compliant
- Gold over Nickel Termination Finish
- Serial ID with Comprehensive Traceability



For more information -- Click on the drawing

Description

The Fox XPRESSO Crystal Oscillator is a breakthrough in configurable Frequency Control Solutions. XPRESSO utilizes a family of proprietary ASICs, designed and developed by Fox, with a key focus on noise reduction technologies.

The 3rd order Delta Sigma Modulator reduces noise to the levels that are comparable to traditional Bulk Quartz and SAW oscillators. The ASICs family has ability to select the output type, input voltages, and temperature performance features.

With the XPRESS lead-time, low cost, low noise, wide frequency range, excellent ambient performance, XpressO is an excellent choice over the conventional technologies.

Finished XPRESSO parts are 100% final tested. FOXElectronics 5570 Enterprise Parkway Fort Myers, Florida 33905 USA +1.239.693.0099 FAX +1.239.693.1554 http://www.foxonline.com





Rev. 3/27/2012

Need a

Applications

- ANY application requiring an oscillator
- SONET
- Ethernet
- Storage Area Network
- Broadband Access
- Microprocessors / DSP / FPGA
- Industrial Controllers
- Test and Measurement Equipment
- Fiber Channel

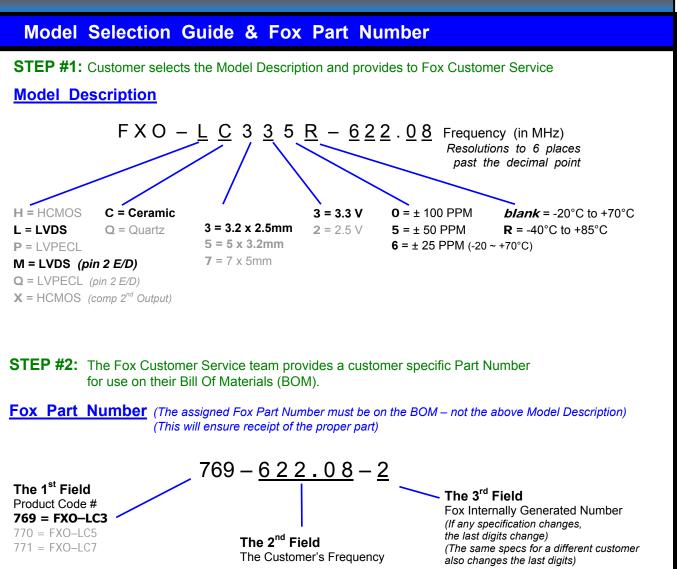
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nana





This example, FXO-LC335R-622.08 = LVDS Output, Ceramic, 3.2 x 2.5mm Package, 3.3V, ±50 PPM Stability, -40 to +85°C Temperature Range, at 622.08 MHz





Electrical Characteristics								
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)					
Frequency Range	Fo		0.750 MHz to 1.35 GHz					
Frequency Stability ¹		0.75 ~ 630.000 MHz (-20 to +70°C) 0.75 ~ 630.000 MHz (-40 to +85°C) 630.000+ MHz ~ 1.350 GHz (-20 to +70°C) 630.000+ MHz ~ 1.350 GHz (-40 to +85°C)	100, 50, 25* PPM 100, 50 PPM 100, 50 PPM 100 PPM					
Temperature Range	T _O T _{STG}	Standard operating <i>Optional operating</i> Storage	-20°C to +70°C -40°C to +85°C -55°C to +125°C					
Supply Voltage	V _{DD}	Standard	3.3 V ± 5%					
Input Current (@ 100 Ohm Load)	I _{DD}	Standard Load	100 mA					
Output Load		Standard	100 Ohms Typ.					
Start-Up Time	Ts		10 mS					
Output Enable / Disable Time			100 nS					
Moisture Sensitivity Level	MSL	JEDEC J-STD-20	1					
Termination Finish			Au					

¹¹nclusive of 25°C tolerance, operating temperature range, input voltage change, load change, aging, shock and vibration. *Excludes aging.

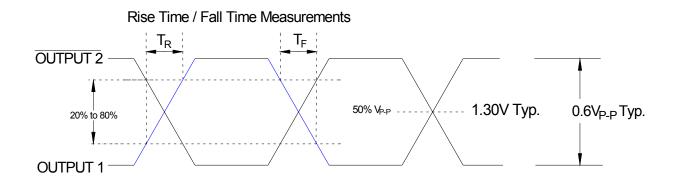
Absolute Maximum Ratings (Useful life may be impaired. For user guidelines only, not tested)							
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)				
Input Voltage	V_{DD}		–0.5V to +5.0V				
Operating Temperature	T _{AMAX}		–55°C to +105°C				
Storage Temperature	T _{STG}		–55°C to +125°C				
Junction Temperature			150°C				
ESD Sensitivity	HBM	Human Body Model	> 1 kV				



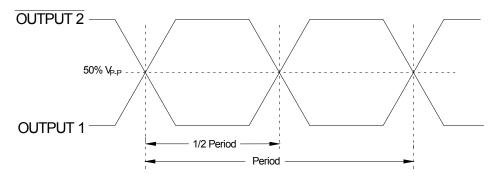


Output Wave Charac			
Parameters	Symbol	Condition	Maximum Value (unless otherwise noted)
Differential Output Voltage	V _{OD}	0.75 MHz to 1.35 GHz	0.6V Typ.
Output Offset Voltage	V _{os}	Volts DC	1.3V Typ.
Output Symmetry (See Drawing Below)		@ 50% V _{P-P} Level	45% ~ 55%
Output Enable (PIN # 1) Voltage Note1	V _{IH}		≥ 70% V _{DD}
Output Disable (PIN # 1) Voltage Note1	V _{IL}		$\leq 30\% V_{DD}$
Cycle Rise Time (See Drawing Below)	T _R	20%~80% Vp-p	400 pS
Cycle Fall Time (See Drawing Below)	T _F	80%~20% Vp-p	400 pS

¹An optional PIN # 2 as Enable / Disable is available – see Model Selection Guide (page 2)



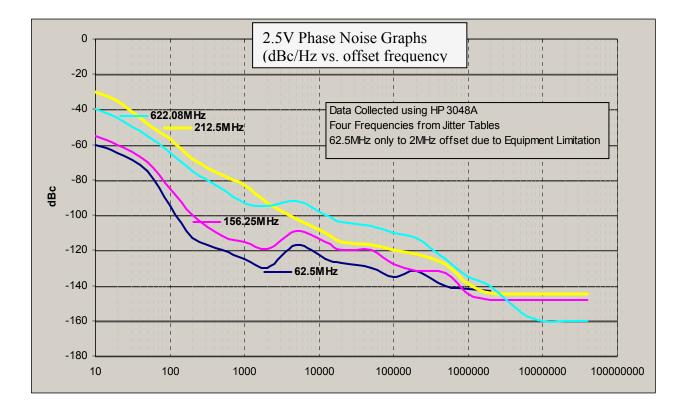
Oscillator Symmetry Ideally, Symmetry should be 50/50 for 1/2 period – Other expressions are 45/55 or 55/45







Phase Noise



Jitter is frequency dependent. Below are typical values at select frequencies.

LVDS Phase	LVDS Phase Jitter & Time Interval Error (TIE)						
Frequency	Phase Jitter (12kHz to 20MHz)	TIE (Sigma of Jitter Distribution)	Units				
62.5 MHz	1.3	2.6	pS RMS				
156.25 MHz	0.6	4.3	pS RMS				
212.5 MHz	0.8	5.0	pS RMS				
622.08MHz	0.7	2.4	pS RMS				

 Phase Jitter
 is integrated from HP3048 Phase Noise Measurement System; measured directly into 50 ohm input; V_{DD} = 3.3V.

 TIE
 was measured on LeCroy LC684 Digital Storage Scope, directly into 50 ohm input, with Amherst M1 software; V_{DD} = 3.3V.

 Per MJSQ spec
 (Methodologies for Jitter and Signal Quality specifications)

LVDS Random & Deterministic Jitter Composition							
Frequency	Random (Rj) (pS RMS)	Deterministic (Dj) (pS P-P)	Total Jitter (Tj) (14 x Rj) + Dj				
62.5 MHz	1.2	11.9	29.1 pS				
156.25 MHz	1.2	11.2	28.4 pS				
212.5 MHz	1.2	12.7	29.8 pS				
622.08 MHz	1.0	9.4	24.5 pS				

<u>**Rj and Dj**</u>, measured on LeCroy LC684 Digital Storage Scope, directly into 50 ohm input, with Amherst M1 software. Per **MJSQ** spec (Methodologies for Jitter and Signal Quality specifications)





		_	
Pin #	Name	Туре	Function
1	E/D ¹	Logic	Enable / Disable Control of Output (0 = Disabled)
2	NC		No Connection – Leave OPEN
3	GND	Ground	Electrical Ground for V _{DD}
4	Output	Output	LVDS Oscillator Output
5	Output 2	Output	Complementary LVDS Output
6	V_{DD}^2	Power	Power Supply Source Voltage
NOTES	1 Includes pull-u	\ensuremath{p} p resistor to V_{DD} to	provide output when the pin (1) is No Connect.
NOTES	1 Includes pull-u 2 Installation sho	ip resistor to V_{DD} to build include a 0.01 μ	
E / D	: ¹ Includes pull-u ² Installation sho (Pin 6) and GN	ip resistor to V_{DD} to build include a 0.01 μ	provide output when the pin (1) is No Connect. F bypass capacitor placed between V _{DD} e power supply line noise.
	: ¹ Includes pull-u ² Installation sho (Pin 6) and GN	ip resistor to V _{DD} to buld include a 0.01μ D (Pin 3) to minimiz	provide output when the pin (1) is No Connect. F bypass capacitor placed between V _{DD} e power supply line noise.

Terminations as viewed from the Top

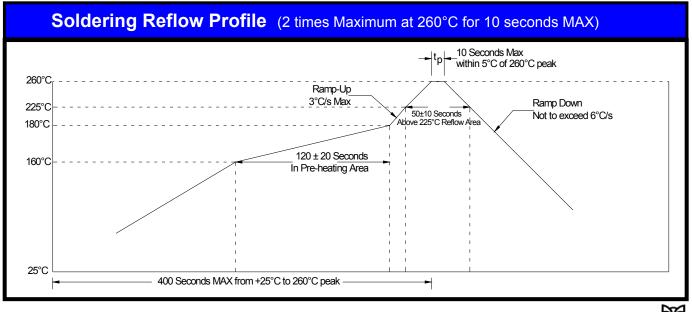
Enable / Disable Control		
Pin # 1 (state)	Output (Pin # 4, Pin # 5)	
OPEN (No Connection)	ACTIVE Output	
"1" Level V _{IH} ≥ 70% V _{DD}	ACTIVE Output	
"0" Level V _{IL} \leq 30% V _{DD}	High Impedance	

GND

#3

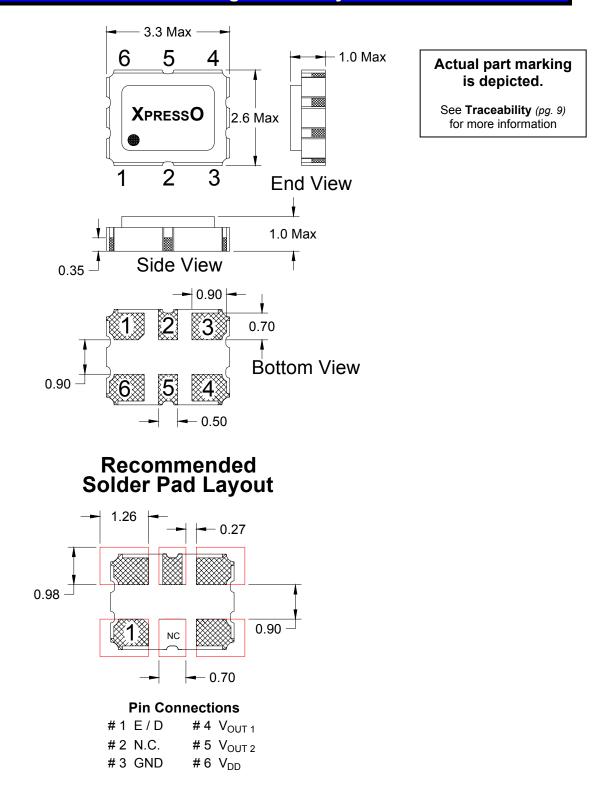
#4

OUTPUT





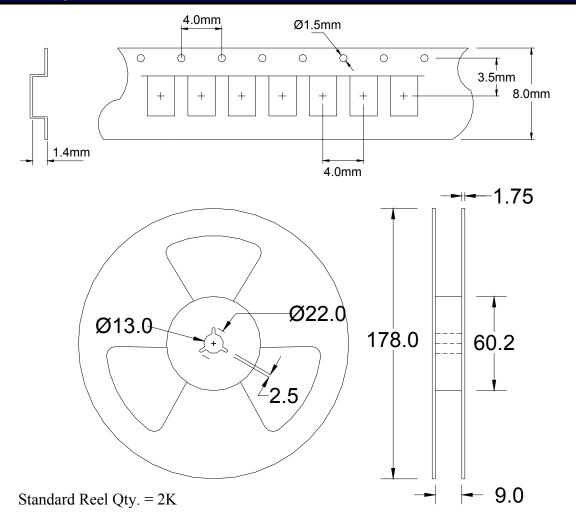
Mechanical Dimensional Drawing & Pad Layout



Drawing is for reference to critical specifications defined by size measurements. Certain non-critical visual attributes, such as side castellations, reference pin shape, etc. may vary



Tape and Reel Dimensions



Labeling (Reels and smaller packaging are labeled with the below)



An additional identification code is contained internally if tracking should ever be necessary





Traceability – LOT Number & Serial Identification

LOT Number

The LOT Number has direct ties to the customer purchase order. The LOT Number is marked on the "Reel" label, and also stored internally on non-volatile memory inside the XPRESSO part. XPRESSO parts that are shipped Tape and Reel, are also placed in an Electro Static Discharge (ESD) bag and will have the LOT Number labeled on the exterior of the ESD bag.

It is recommended that the XPRESSO parts remain in this ESD bag during storage for protection and identification.

If the parts become separated from the label showing the LOT Number, it can be retrieved from inside one of the parts, and the information that can be obtained is listed below:

- Customer Purchase Order Number
- Internal Fox Sales Order Number
- Dates that the XPRESSO part was shipped from the factory
- The assigned customer part number
- The specification that the part was designed for

Serial Identification

The Serial ID is the individualized information about the configuration of that particular XPRESSO part. The Serial ID is unique for each and every XPRESSO part, and can be read by special Fox equipment.

With the Serial ID, the below information can be obtained about that individual, XPRESSO part:

- Equipment that the XPRESSO part was configured on
- Raw material used to configure the XPRESSO part
- Traceability of the raw material back to the foundries manufacturing lot
- Date and Time that the part was configured
- Any optimized electrical parameters based on customer specifications
- Electrical testing of the actual completed part
- Human resource that was monitoring the configuration of the part

Fox has equipment placed at key Fox locations World Wide to read the Lot Identification and Serial Number of any XPRESSO part produced and can then obtain the information from above within 24 hours





3rd Party (SGS) Material Report **Test Report** No.: CE/2008/63138 Date: 2008/06/19 Page: 1 of 4 FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA The following sample(s) was/were submitted and identified by/on behalf of the client as : Sample Description : XPRESSO CERAMIC OSCILLATORS Style/Item No. : SEAM SEAL CLOCK OSCILLATOR Buyer/Order No. : 47454 : 2008/06/12 Sample Receiving Date Testing Period : 2008/06/12 TO 2008/06/19 Test Result(s) Please refer to next page(s). : Chenyu Kung / Operation Manager Signed for and on behalf of SGS TAIWAN LTD. Chemical Laboratory – Taipei Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company. 除非为有我明,此能告结果做到做就之体品负责,本种最大都不公司書面許可,不可能的機要。 This Test Report is issued by the Company under its General Conditions of Service printed overleaf or available on request and accessible at <u>intru-wave ops com/tems</u>, and <u>conditions time</u>. Attention is drawn to the limitation of liability, indemrification and jurisdiction issues defined therein. Any holder of this Test Report is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Client's instructions, if any. The Company's sole responsibility is to its Client and this document does not exponse parties to a transaction from exercising all their rights and obligations under the transaction documents. Any under the transaction documents, any unauthorized ateration, forgery or tailsfication of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law.
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FXO-LC33 Series

3rd Party (SGS) Material Report (continued)



Test Report

No.: CE/2008/63138 Date: 2008/06/19 Page: 2 of 4

FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA

Test Result(s)

PART NAME NO.1

: MIXED ALL PARTS

Test Item (s):	Unit	Method	MDL	Result
Test Reiff (s).	Unit	Metrod	MDL	No.1
Cadmium (Cd)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Cadmium by ICP-AES.	2	n.d.
Lead (Pb)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Lead by ICP-AES.	2	n.d.
Mercury (Hg)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Mercury by ICP-AES.	2	n.d.
Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Hexavalent Chromium for non- metallic samples by UV/Vis Spectrometry.	2	n.d.
Halogen		With reference to BS EN 14582:2007. Analysis was performed by IC method for F, CI, Br, I content.		
Halogen-Fluorine (F) (CAS No.: 007782-41-4)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Fluorine content.	50	n.d.
Halogen-Chlorine (CI) (CAS No.: 007782-50-5)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Chlorine content.	50	n.d.
Halogen-Bromine (Br) (CAS No.: 007726-95-6)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Bromine content.	50	n.d.
Halogen-Iodine (I) (CAS No.: 007553-56-2)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for lodine content.	50	n.d.

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3rd Party (SGS) Material Report (continued)



Test Report

No.: CE/2008/63138 Date: 2008/06/19 Page: 3 of 4

FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA

Test Item (s):	Unit	Method	MDL	Result
Test Rem (s):	Onit	Method	MDL	No.1
Sum of PBBs	-			n.d.
Monobromobiphenyl			5	n.d.
Dibromobiphenyl			5	n.d.
Tribromobiphenyl			5	n.d.
Tetrabromobiphenyl	1		5	n.d.
Pentabromobiphenyl	1	I F	5	n.d.
Hexabromobiphenyl		I F	5	n.d.
Heptabromobiphenyl	1	I F	5	n.d.
Octabromobiphenyl	1	I F	5	n.d.
Nonabromobiphenyl	1	I F	5	n.d.
Decabromobiphenyl	1	With reference to IEC 62321/2nd	5	n.d.
Sum of PBDEs (Mono to Nona)	mg/kg	CDV (111/95/CDV). Determination of	-	n.d.
Monobromodiphenyl ether	1	PBB and PBDE by GC/MS.	5	n.d.
Dibromodiphenyl ether	1	I F	5	n.d.
Tribromodiphenyl ether	1	I F	5	n.d.
Tetrabromodiphenyl ether	1	I F	5	n.d.
Pentabromodiphenyl ether	1	I T	5	n.d.
Hexabromodiphenyl ether	1	I F	5	n.d.
Heptabromodiphenyl ether	1		5	n.d.
Octabromodiphenyl ether		I F	5	n.d.
Nonabromodiphenyl ether	1	I F	5	n.d.
Decabromodiphenyl ether	1	I F	5	n.d.
Sum of PBDEs (Mono to Deca)	1	I F	(1	n.d.

Note : 1. mg/kg = ppm

2. n.d. = Not Detected

3. MDL = Method Detection Limit

4. "---" = Not Conducted

5. " - " = Not Regulated

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FXO-LC33 Series

Party (SGS) Material Report (continued) 3rd **Test Report** No.: CE/2008/63138 Date: 2008/06/19 Page: 4 of 4 FOX ELECTRONICS 5570 ENTERPRISE PARKWAY FT. MYERS, FL 33905, USA CE/2008/63138 Olumbun 1Cm ** End of Report ** Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company. 除非另有原则,也保着给某保备到就之保品负责,中期位未根本公司者面折可,不可定价规则。 This Test Report is Except in Sued by the Company under its General Conditions of Service printed overleaf or available on request and accessible at <u>http://www.sgs.com/tems_and_conditions.itm</u>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this Test Report is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Clerk's instructions, if any. The Company's sole responsibility is to its Clerk and the tand this document does not excensive parties to a transaction from exercising at their rights and obligations under the transaction documents. Any unauthorized ateration, forgery or faisification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. SGS Taiwan Ltd. No. 33 Wu Chyuan Road, Wuku Industrial Zone, Taipel County, Taiwan / 台北縣五股工 樂園五橋路 33 號 台灣檢驗科技股份有限公司 t (886-2) 2299-3939 f (886-2) 2299-3237 www.tw.sgs.com Member of the SGS Group



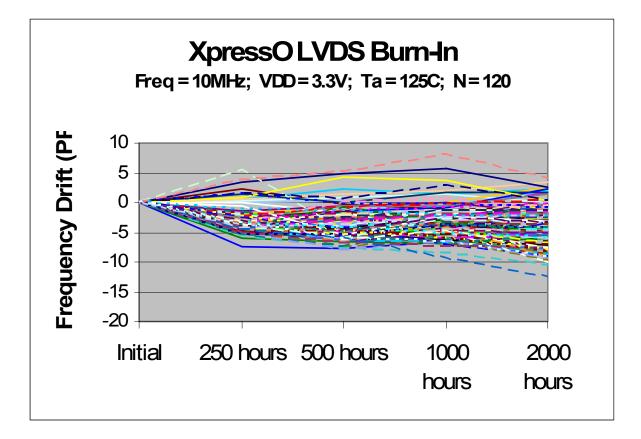


Mechanical Testing

Parameter	Test Method
Mechanical Shock	Drop from 75cm to hardwood surface – 3 times
Mechanical Vibration	10~55Hz, 1.5mm amplitude, 1 Minute Sweep 2 Hours each in 3 Directions (X, Y, Z)
High Temperature Burn-in	Under Power @ 125°C for 2000 Hours (results below)
Hermetic Seal	He pressure: 4 ±1 kgf / cm ² 2 Hour soak

2,000 Hour Burn-In

Burn-In Testing – under power 2000 Hours, 125°C







MTTF / FITS Calculations

Products are grouped together by process for MTTF calculations. (All XpressO output and package types are manufactured with the same process)

Number of Parts Tested: 360 (120 of each output type: HCMOS, LVDS, LVPECL) Number of Failures: 0 Test Temperature: 125°C Number of Hours: 2000

MTTF was calculated using the following formulas:

[1.] Device Hours (devhrs) = (number of devices) x (hours at elevated temperature in °K)

[2.] $MTTF = \frac{devhrs \times af \times 2}{\chi^2}$ [3.] FITS = $\frac{1}{MTTF}$ * 10⁹

$$3.$$
 $FIIS = \frac{1}{MTT}$

Where:

Label	Name	Formula/Value
af	Acceleration Factor	$\boldsymbol{\varrho}^{(\frac{eV}{k})\times(\frac{1}{t_1}-\frac{1}{t_2})}$
eV	Activation Energy	0.40 V
k	Bolzman's Constant	8.62 X 10⁻⁵ <i>eV</i> /°K
t ₁		Operating Temperature (°K)
t ₂		Accelerated Temperature (°K)
Θ	Theta	Confidence Level (60% industry standard)
r	Failures	Number of failed devices
X ²	Chi-Square	statistical significance for bivariate tabular analysis [table look- up] based on assumed Θ (Theta – confidence) and number of failures (r) For zero failures (60% Confidence): χ^2 = 1.830

DEVICE-HOURS = 360 x 2000 HOURS = 720,000

ACCELERATION FACTOR = $e^{(\frac{0.40}{8.625}) \times (\frac{1}{298} - \frac{1}{398})} = 49.91009$

MTTF = $\frac{720,000 \times 49.91009 \times 2}{2}$ = 39,209,238 Hours 1.833

Failure Rate = $\frac{1.833}{720,000 \times 49.91009 \times 2}$ = 2.55E-8

FITS = Failure Rate *1E9 = 26





Patent Numbers: US 6,664,860, US 5,960,403, US 5,952,890; US 5,960,405; US 6,188,290; Foreign Patents: R.S.A. 98/0866, R.O.C. 120851; Singapore 67081, 67082; EP 0958652 China ZL 98802217.6, Malaysia MY-118540-A, Philippines 1-1998-000245, Hong Kong #HK1026079, Mexico #232179 US and Foreign Patents Pending XpressO™ Fox Electronics

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The above specifications, having been carefully prepared and checked, is believed to be accurate at the time of publication; however, no responsibility is assumed by Fox Electronics for inaccuracies.

